# **Beamline 33-BM / UNI-CAT**

Scientific focus: Materials science and condensed matter physics

**Scientific programs:** Materials science, ceramic science, phase transitions, surface science, thin-film structure and growth, and materials physics

# **Optics & Optical Performance**

- 4–40 keV energy range
- focused beam size 280 µm hor. x 1.4 mm vert.
- collimating mirror

0–6 mrad angle of incidence up to 5 mrad hor. acceptance Pd coating internal water cooling

• PSL double-crystal monochromator

4–40 keV energy range  $10^{-4}$  energy resolution ( $\Delta$ E/E) 30–80 mm beam offset focused beam size 1.4 mm vert. X 0.28 mm hor. magnified beam size 40 mm vert. X 120 mm hor.

focusing mirror

0–6 mrad angle of incidence up to 5 mrad hor. acceptance Pd coating

# Experiment Stations

#### 33-BM-B

- EXAFS
- topography station

#### 33-BM-C

• general purpose scattering station

### **Detectors**

- NaI scintillation counters
- gas-filled proportional counters (Xe, Ar)
- ionization chambers

## **Beamline Controls and Data Acquisition**

• Sun UNIX running EPICS with VME, SPEC

# Beamline Support Equipment/Facilities 33-RM-R

topography station

#### 33-BM-B

• EXAFS table

#### 33-BM-C

• Huber 4-circle diffractometer

## **Bending Magnet Source Characteristics** (nominal)

source	APS bending magnet
critical energy	19.51 keV
on-axis peak brilliance at 16.3 keV	2.9 x 10 <sup>15</sup> ph/sec/mrad <sup>2</sup> /mm <sup>2</sup> /0.1%bw
on-axis peak angular flux at 16.3 keV	$9.6 \times 10^{13}$ ph/sec/mrad%0.1%bw
on-axis peak horizontal angular flux at 5.6 keV	$1.6 \times 10^{13}$ ph/sec/mradh/0.1%bw
source size at critical energy $\sum_{x} \sum_{y} x$	$145~\mu{ m m}$ $36~\mu{ m m}$
source divergence at critical	
$\begin{array}{c} \text{energy} \\ \sum_{x'} \\ \sum_{y'} \end{array}$	6 mrad 47 <i>µ</i> rad